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Posted Date: 12 July 2023

doi: 10.20944/preprints202306.0834.v2

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Concept Paper

# Measuring the Uniformity of Measurable Subsets of the Unit Square

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**Abstract:** Suppose set  $A \subseteq [0, 1] \times [0, 1]$ . We want to define a measure of uniformity of  $A$  in the unit square. In order to understand *uniformity*, we'll give examples in §0 where  $A$  is uniform in  $[0, 1]^2$ . Next in §1, we will define preliminary definitions (e.g. Hausdorff measure) to define uniformity of measurable subsets of the unit square. Finally, in §2 we'll define a measure of uniformity that measures the "distance" from uniformity between 0 and 1 (where the larger the "distance", the larger the non-uniformity).

**Keywords:** spatial; dimensions; uniform distribution; measure theory; hausdorff dimension; sparse

## 0. Intro

The aim of this paper is to measure the "uniformity" of measurable subsets of  $[0, 1]^2$ . If set  $A \subseteq [0, 1] \times [0, 1]$ ; we want to define a measure of uniformity for  $A$ .

Here are some example of a "uniform  $A$ ":

- (1)  $A_n$  is the uniform distribution on the uniform grid  $G_n := \left\{ \left( \frac{i}{n}, \frac{j}{n} \right) : i = 0, \dots, n, j = 0, \dots, n \right\}$  such that with large  $n$ , if  $A_n \rightarrow A$ , then  $A$  is *uniform* in  $[0, 1]^2$
- (2) For all real  $x_1, x_2, y_1, y_2$ , if  $0 \leq x_1 < x_2 \leq 1$  and  $0 \leq y_1 < y_2 \leq 1$  where the Lebesgue measure (on the Lebesgue sigma-algebra) of  $([x_1, x_2] \times [y_1, y_2]) \cap A$  is  $(x_2 - x_1)(y_2 - y_1)$ , then set  $A$  is *uniform* in  $[0, 1] \times [0, 1]$ .

(In general, we shall define a "uniform" subset of  $[0, 1]^2$  in def. 4, §2,).

Note we wish for a measure of uniformity to be between (and including) zero and one or zero and infinity such that the larger the measure, the larger the *non-uniformity*.

Further note, there are already several measures of uniformity for *finite* points in the unit square (e.g. wasserstein distance [1] or distance between empirical copula & independence copula [2]) but no measure for *infinite* points in the unit square.

## 1. Preliminary Definitions

**Definition 1 (Hausdorff Measure).** Let  $(X, \alpha)$  be a metric space,  $\alpha \in [0, \infty)$ . For every  $C \in X$ , define the diameter of  $C$  as:

$$\text{diam}(C) := \sup \{ \varphi(x, y) : x, y \in C \}, \quad \text{diam}(\emptyset) := 0$$

If  $i \in \mathbb{N}$  and  $\delta \in \mathbb{R}$  such that  $\delta > 0$ , where the Euler's Gamma function is  $\Gamma$  and constant  $\mathcal{N}_\alpha$  is:

$$\mathcal{N}_\alpha = \frac{\pi^{\alpha/2}}{\Gamma\left(\frac{\alpha}{2} + 1\right)} \quad (1.0.1)$$

we define:

$$\mathcal{H}_\delta^\alpha(E) = \mathcal{N}_\alpha \inf \left\{ \sum_{i=1}^{\infty} (\text{diam}(C_i))^\alpha : \text{diam}(C_i) \leq \delta, E \subseteq \bigcup_{i=1}^{\infty} C_i \right\} \quad (1.0.2)$$

such if the infimum of the equation is taken over the countable covers of sets  $C_i \subset X$  of  $E$  (satisfying  $\text{diam}(C_i) \leq \delta$ ), the Hausdorff Outer Measure is:

$$\mathcal{H}^\alpha(E) = \sup_{\delta > 0} \mathcal{H}_\delta^\alpha(E) = \lim_{\delta \rightarrow 0} \mathcal{H}_\delta^\alpha(E)$$

where for  $\alpha \in \mathbb{N}$ ,  $\mathcal{H}^\alpha(E)$  coincides with the  $\alpha$ -dimensional Lebesgue Measure, where we convert the Outer measure to the Hausdorff measure from restricting  $E$  to the  $\sigma$ -field of Carathéodory measurable sets [3].

**Definition 2 (Hausdorff Dimension).** The Hausdorff Dimension of  $E$  is defined by  $\phi(E)$  where:

$$\mathcal{H}^d(E) = \begin{cases} \infty & \text{if } 0 \leq d < \phi(E) \\ 0 & \text{if } \phi(E) < d < \infty \end{cases} \quad (1.0.3)$$

### 1.1. Generalized Hausdorff Measure

If  $\mathcal{H}^{\phi(E)}(E)$  is zero or infinity, consider the following:

**Definition 3 (Generalized Hausdorff Measure).** Suppose  $(X, d)$  is a metric space. Let  $h : [0, \infty) \rightarrow [0, \infty)$  be an (exact) dimension function (or gauge function) which is monotonically increasing, strictly positive, and right continuous [4].

For  $i \in \mathbb{N}$ , where  $\delta \in \mathbb{R}$  and  $\delta > 0$ , if the Hausdorff dimension is  $\phi(E)$ ; we define:

$$\mathcal{H}_\delta^h(E) = \mathcal{N}_{\phi(E)} \inf \left\{ \sum_{i=1}^{\infty} h(\text{diam}(C_i)) : \text{diam}(C_i) \leq \delta, E \subseteq \bigcup_{i=1}^{\infty} C_i \right\} \quad (1.1.1)$$

such if the infimum of the equation above is taken over the countable covers of sets  $C_i \subset X$  of  $E$  (which satisfy  $\text{diam}(C_i) \leq \delta$ ), the  $h$ -Hausdorff Outer Measure follows:

$$\mathcal{H}^h(E) = \sup_{\delta > 0} \mathcal{H}_\delta^h(E) = \lim_{\delta \rightarrow 0} \mathcal{H}_\delta^h(E) \quad (1.1.2)$$

where when  $\phi(E) \in \mathbb{N}$ ,  $\mathcal{H}^h(E)$  should coincide with the  $\phi(E)$ -dimensional Lebesgue Measure such that we define the "outer  $h$ -Hausdorff measure" as  $h$ -Hausdorff measure by restricting the Outer Measure to  $E$  measurable in the sense of Carathéodory, where  $\mathcal{H}^h(E)$  is strictly positive and finite.

## 2. Measuring "Uniformity" of a Measurable Subset of $[0, 1] \times [0, 1]$

Using this answer [5], let  $S := [0, 1]^2$  be the unit square. "Partition"  $S$  naturally into four congruent squares  $S_{1,j}$  (with side length  $1/2$  each), where  $j = 1, \dots, 4$ ; the quotation marks are used here because the  $S_{1,j}$ 's will have some common boundary points. Next, "partition" each  $S_{1,j}$  naturally into four congruent squares (with side length  $1/2^2$  each), so that we get  $4^2$  squares  $S_{2,j}$  for  $j = 1, \dots, 4^2$ . Continue doing so, so that at the  $k$ th step we get  $4^k$  squares  $S_{k,j}$  for  $j = 1, \dots, 4^k$ , for each  $k = 1, 2, \dots$ .

Take any subset  $A$  of  $S$ . For each  $k = 1, 2, \dots$  and each  $j = 1, \dots, 4^k$ , let

$$A_{k,j} := (A \cap S_{k,j}) - s_{k,j},$$

where  $s_{k,j}$  is the southwest vertex of the square  $S_{k,j}$ , so that  $A_{k,j} \subseteq S_k := 2^{-k}S$ .

Suppose that for each  $k$  we have a "measure"  $D_k$  of dissimilarity for subsets of  $S_k$ , so that for any two subsets  $B$  and  $C$  of  $S_k$  we have a nonnegative real number  $D_k(B, C)$ , which is the greater the more "dissimilar"  $B$  and  $C$  are (and is 0 if  $B = C$ ); here the term "measure" is used in the general sense, not necessarily in the sense of measure theory. For instance,  $D_k(B, C)$  may depend on the Hausdorff distance [6] between  $B$  and  $C$  or on some "measure" of the symmetric difference of the sets  $B$  and  $C$  or on some combination thereof.

Then the distance of the set  $A$  from uniformity can be defined by the formula

$$D(A) := \sum_{k=1}^{\infty} \frac{1}{L^k} \sum_{j=1}^{4^k} \sum_{m=1}^{4^k} \frac{D_k(A_{k,j}, A_{k,m})}{1 + D_k(A_{k,j}, A_{k,m})},$$

where  $L$  is a real number  $> 16$  (to ensure the convergence of the series). Then  $D(A)$  will be small if, for "most" levels  $k$  of "zooming", "most" of the intersections of the set  $A$  with all the " $k$ -level" small squares  $S_{k,j}$  "look similar" to one another. In other terms:

**Definition 4 (Definition of Uniform  $A$  in The Unit Square).** If  $D(A) = 0$ ,  $A$  is uniform in  $[0, 1]^2$ .

(Of course,  $D(A)$  will depend on the choices of  $L$  and the dissimilarity "measures"  $D_k$ .)

For instance, for any  $L$  and any  $D_k$ 's we have  $D(S) = 0$  – of course, the unit square  $S$  is at distance 0 from uniformity (in itself).

As another example, for the uniform grid  $G_n$  (defined in §0, crit. (0)) with  $n = 2^K$  for a natural  $K$ , any real  $L > 16$ , and any  $D_k$ 's we have

$$D(G_n) \leq \sum_{k=K+1}^{\infty} \frac{1}{L^k} 16^k = Cn^{-p} \rightarrow 0$$

as  $n = 2^K \rightarrow \infty$ , where  $C := \frac{16}{L-16}$  and  $p := \log_2 \frac{L}{16}$ .

### 2.1. Specific Example of Measure of Uniformity for Measurable Subsets of $[0, 1]^2$

For example, if  $D_k$  is  $\mathcal{H}^h$  (def. 3) where  $h$  is the dimension function of  $A$  and  $L = 32$ , one measure of uniformity is:

$$D(A) := \sum_{k=1}^{\infty} \frac{1}{32^k} \sum_{j=1}^{4^k} \sum_{m=1}^{4^k} \frac{\mathcal{H}^h(A_{k,j} \Delta A_{k,m})}{1 + \mathcal{H}^h(A_{k,j} \Delta A_{k,m})},$$

where if  $\mathcal{H}^h(A_{k,j} \Delta A_{k,m}) = +\infty$  for some  $k, j, m \in \mathbb{N}$  or if  $\mathcal{H}^h(A_{k,j} \Delta A_{k,m}) = 0$  for all  $k, j, m \in \mathbb{N}$ , take §3 of this paper [7] (if version 3 of the paper exists, consider *that* version instead).

In [7], for (§3, eq. 4.1.9) if we replace  $k$  with  $z$ , such that  $(F_z^{***})$  is a chosen sequence from a set of equivalent  $\star$ -sequence of sets (§2, def. 4), this should give us:

$$\forall(\epsilon > 0) \exists(N \in \mathbb{N}) \forall(z \in \mathbb{N}) \left( z \geq N \Rightarrow \left| D^*(A) - \sum_{k=1}^{\infty} \frac{1}{32^k} \sum_{j=1}^{4^k} \sum_{m=1}^{4^k} \frac{\mathcal{H}^h((A_{k,j} \Delta A_{k,m}) \cap F_z^{***})}{1 + \mathcal{H}^h((A_{k,j} \Delta A_{k,m}) \cap F_z^{***})} \right| \leq \epsilon \right)$$

where  $D^*(A)$  is the **final measure of uniformity** for subset of the unit square (if it exists).

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